

CYPRESS SEMICONDUCTOR CORPORATION

PRODUCT RELIABILITY REPORT

QUARTER 3, 1999



PERFORM PER THE REQUIREMENT OF 25-00008, RELIABILITY MONITOR PROGRAM SPECIFICATION

Ed Russell
Reliability Director

STANDARD STRESS TEST DESCRIPTIONS

<u>TEST</u>	<u>DESCRIPTION</u>
HTOL	High Temp Op Life, 150°C, Dynamic 115% V _{CC} Nominal
HTOL2	High Temp Op Life, 125°C, Dynamic 115% V _{CC} Nominal
HTSSL	High Temp Steady State Life, 150°C, Static 115% V _{CC} Nominal
HTSSL2	High Temp Steady State Life, 125°C, Static 115% V _{CC} Nominal
DRET	Data Retention Test, Data Bake 165°C, Plastic
DRET2	Data Retention Test, Data Bake 250°C, Hermetic
PCT	Pressure Cooker Test, 121°C, 100%RH, No Bias
HAST	Hi-Accel Saturation Test, 140°C/130°C, 85%RH, Static 100% V _{CC} Nominal
TC	Temp Cycle, 125°C to -40°C
TC2	Temp Cycle, 150°C to -65°C
HTS	High Temp Storage, 150°C, No Bias

WAFER FAB AREAS

<u>FAB #</u>	<u>LOCATION</u>
CA	San Jose, California
TX	Round Rock, Texas
MN	Bloomington, Minnesota
TW	TSMC, Taiwan

ASSEMBLY LOCATION

<u>ID</u>	<u>COMPANY/LOCATION</u>
KOREA-A	Anam-Buchon/Korea
ASAT-B	Asat/Hongkong
USA-C	Cypress/USA
PHIL-D	Dynesem/Philippines
USA-E	Cypress-Minnesota/USA
INDNS-F	Astra/Indonesia
TAIWAN-G	ASE/Taiwan
KOREA-H	Hyundai/Korea
MALAY-J	ASE/Malaysia
THLAND-AK	TMS/Thailand
KOREA-L	Anam-Seoul/Korea
PHIL-M	Anam/Philippines
USA-N	Express/USA
INDNS-O	Omedata/Indonesia
USA-P	Pantronix/USA
KOREA-Q	Anam-Bupyong/Korea
PHIL-R	Cypress/Philippines
USA-S	ATM/USA
TAIWAN-T	OSE/Taiwan
MALAY-U	Unisem/Malaysia
USA-V	VLSA/USA
USA-W	Toshiba/USA
ALPHA-X	Alphatec/Thailand
THLAND-Z	Hana/Thailand
USA-AP	APLUS/USA
KOREA-GQ	Anam-Khangju/Korea
PHIL-GW	Gateway Electronics/Philippines

DESCRIPTION OF DATA TABLE COLUMN HEADINGS

<u>COLUMN HEADING</u>	<u>DESCRIPTION OF COLUMN CONTENTS</u>
Division	Cypress Manufacturing Division
Test	Common code for the stress performed. See table on previous page for detail.
Test Condition	Tem/humidity/bias condition for the stress. See table on previous for detail
Device ID	Cypress part number
Date Code	Week in which specific lot was marked/sealed/molded.
Lot Number	Manufacturing (assembly) lot number
Function	Generic product family at Cypress
Description	Brief description of device function
Technology	Fabrication process technology.
Process	Generic fabrication process
Pkg Material	Generic packaging material
Pkg Type	Common code for standard package configuration (PDIP=Plastic Dual-In-Line-Package).
Pkg Location	Country Location + Initial of assembly house (see table on previous page for detail).
# Pins	Pin count of package in which device is assembled.
Duration	Data Readpoint of stress. For Temp Cycle (TC) = Cycles; all other stresses=Hours.
# Test	Quantity of devices submitted to this stress/test.
# Failed	Quantity of devices failing at this specific readpoint.
Fail Mode	Failure analysis results from this test, if any.

RELIABILITY DATA SUMMARY (Q399)

LONG TERM FAILURE RATE SUMMARY					
PROCESS	DEVICE HOURS			FAILED	FAILURE MODE
	150C	125C	TOTAL* @ 150C		
E2PROM TOTAL	0	0	0	0	
FAMOS TOTAL	0	0	0	0	
FLASH TOTAL	0	0	0	0	
SRAM/LOGIC TOTAL	4,707,676	0	4,707,676	9	1 PLASTIC PACKAGE DEFECT/1 SOLDERABILITY/1 EXCESS INTERMETALLICS/3 UNKNOWN CAUSE/2 GATE OXIDE RUPTURE/1 PARTICLE DEFECT/1 FA PENDING
BICMOS TOTAL	0	0	0	0	
LFR TOTAL	4,707,676	0	4,707,676	9	1 PLASTIC PACKAGE DEFECT/1 SOLDERABILITY/1 EXCESS INTERMETALLICS/3 UNKNOWN CAUSE/2 GATE OXIDE RUPTURE/1 PARTICLE DEFECT/1 FA PENDING
EARLY FAILURE RATE SUMMARY					
PROCESS	UNITS TESTED			FAILED	FAILURE MODE
	150C	125C	TOTAL @ 150C		
E2PROM TOTAL	0	0	0	0	
FAMOS TOTAL	2,564	809	3,373	0	
FLASH TOTAL	0	0	0	0	
SRAM/LOGIC TOTAL	55,353	4,545	59,898	6	2 UNKOWN CAUSE/2 PARTICLE DEFECTS/1 FAB DEFECT/1 FA PENDING
BICMOS TOTAL	0	0	0	0	
EFR TOTAL	57,917	5,354	63,271	6	2 UNKOWN CAUSE/2 PARTICLE DEFECTS/1 FAB DEFECT/1 FA PENDING
HTSSL FAILURE RATE SUMMARY					
PROCESS	DEVICE HOURS			FAILED	FAILURE MODE
	150C	125C	TOTAL* @ 150C		
FAMOS TOTAL	0	0	0	0	
FLASH TOTAL	0	0	0	0	
SRAM/LOGIC TOTAL	26,800	0	26,800	0	
BICMOS TOTAL	0	0	0	0	
HTSSL TOTAL	26,800	0	26,800	0	

RELIABILITY DATA SUMMARY (Q399)

TEMP CYCLE FAILURE RATE SUMMARY					
PROCESS	DEVICE CYCLE			FAILED	FAILURE MODE
	150C	125C	TOTAL * @ 150C		
E2PROM	12,900	0	12,900	0	
FAMOS TOTAL	141,600	0	141,600	0	
FLASH TOTAL	67,500	0	67,500	0	
SRAM/LOGIC TOTAL	821,800	216,000	877,960	2	1 MISSING SOLDER BALL/1 UNKNOWN CAUSE
BICMOS TOTAL	27,000	0	27,000	0	
TC TOTAL	1,070,800	216,000	1,126,960	2	1 MISSING SOLDER BALL/1 UNKNOWN CAUSE
HAST FAILURE RATE SUMMARY					
PROCESS	DEVICE HOURS			FAILED	FAILURE MODE
	140C	130C	TOTAL* @ 140C		
E2PROM	0	0	0	0	
FAMOS TOTAL	23296	0	23296	0	
FLASH TOTAL	5,760	0	5,760	0	
SRAM/LOGIC TOTAL	128,128	12,160	134,585	1	1 UNKNOWN CAUSE
BICMOS TOTAL	11,392	0	11,392	0	
HAST TOTAL	168,576	12,160	175,033	1	1 UNKNOWN CAUSE
LTOL FAILURE RATE SUMMARY					
PROCESS	DEVICE HOURS			FAILED	FAILURE MODE
FAMOS TOTAL	0			0	
FLASH TOTAL	0			0	
SRAM/LOGIC TOTAL	0			0	
BICMOS TOTAL	0			0	
LTOL TOTAL	0			0	
PCT FAILURE RATE SUMMARY					
PROCESS	DEVICE HOURS			FAILED	FAILURE MODE
E2PROM	0			0	
FAMOS TOTAL	66,864			2	1 UNKNOWN CAUSE/1 BENT LEADS
FLASH TOTAL	30,240			0	
SRAM/LOGIC TOTAL	281,232			1	1 OVER BOND/CRATERING
BICMOS TOTAL	7,560			0	
PCT TOTAL	385,896			3	1 UNKNOWN CAUSE/1 BENT LEADS/1 OVER BOND/CRATERING

* Equivalent Total Device Hours/Cycles. Derating factors are used for lower stress conditions.

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Technology	Test	Test Condition	Division	Function	Device	Eval#	D/C	Assembly Lot No	Description	Process	Wfr Loc	Pkg type	Assy Loc	No Pin	Duration	Qty Test	Qty Fail	Fail Mode

BICMOS-SM1	HAST	140/5.5V	DCD	CHNL	CY7B991-JC	MR92125	9903	219900322	PSCB	BiCMOS	TX	PLCC	ALPHA-X	32	128	44	0	
		140C/5.5V	DCD	CHNL	CY7B991-JC	MR93213	9932	619922425	PSCB	BiCMOS	TX	PLCC	ALPHA-X	32	128	45	0	

	PCT	121C/100%RH	DCD	CHNL	CY7B991-JC	MR93211	9932	619922425	PSCB	BiCMOS	TX	PLCC	ALPHA-X	32	168	45	0	

	TC2	-65C TO 150C	DCD	CHNL	CY7B991-JC	MR91117	9907	619903134	PSCB	BiCMOS	TX	PLCC	ALPHA-X	32	300	45	0	
					CY7B991-VC	MR92110	9830	219805230	PSCB	BiCMOS	TX	PLCC	ALPHA-X	32	300	45	0	

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E2PROM-E3	TC2	-65C TO 150C	PLD	37K	CY37256P256-BGC	MR92135	9904 619900830	256 MCEL	CMOS	TW	BGA	TAIWAN-G	292	300	43	0	

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FAMOS-P20	HAST	140C/5.5V	PLD	MAX	CY7C341-JC	MR92174	9915 619908941	REPROG.PAL	CMOS	TX	PLCC	KOREA-A	84	128	42	0	
	HTOL2	125C/5.75V	PLD	MAX	CY7C346-JC	99211	9924 619915399	REPROG.PAL	CMOS	TX	PLCC	ALPHA-X	84	96	296	0	1 EOS
							9931 619920149	REPROG.PAL	CMOS	TX	PLCC	ALPHA-X	84	96	193	0	
	HTS2	150C/NO BIAS	PLD	PLD	PALC22V10B-15PC	MR93023	9925 519911235	REPROG. PAL	CMOS	TX	PDIP	INDNS-O	24	500 1000	41 41	0	4 EOS
	PCT	121C/100%RH	PLD	MAX	CY7C341-JC	MR92172	9915 619908941	REPROG.PAL	CMOS	TX	PLCC	KOREA-A	84	168	45	1	1 Unknown Cause
					CY7C344-JI	MR93058	9927 619918944	REPROG.PAL	CMOS	TX	PLCC	ALPHA-X	28	168	45	0	
			PLD		PALC22V10B-15PC	MR93021	9925 519911235	REPROG. PAL	CMOS	TX	PDIP	INDNS-O	24	168	40	0	5 EOS
	TC2	-65C TO 150C	PLD	MAX	CY7C344-JI	MR93059	9927 619918944	REPROG.PAL	CMOS	TX	PLCC	ALPHA-X	28	300	45	0	
			PLD		PALC22V10B-15PC	MR93022	9925 519911235	REPROG. PAL	CMOS	TX	PDIP	INDNS-O	24	300	45	0	

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FAMOS-P26	HAST	140C/5.5V	IPD	USB	CY7C63001A-SC	MR93017	9926 619918207	USB	CMOS	TX	SOIC	CSPI-R	20	128	45	0	
					CY7C63613-SC	MR93080	9928 619919235	USB	CMOS	TX	SOIC	CSPI-R	24	128	45	0	
					CY7C66113-PVC	99241	9925 619916424	FULL SP USB	CMOS	TX	SSOP	CSPI-R	56	128	50	0	
	HTOL	150C/5.75V	IPD	PCTRL	CY7C69100	98352	9852 519816422	MICROCTRL	FAMOS	TX	PDIP	INDNS-O	24	48	33	0	
														48	446	0	
														48	525	0	
				USB	CY7C65113-SC	99277	9925 619915318	USB HUB	CMOS	TX	SOIC	ALPHA-X	28	48	520	0	
							9928 519912085	USB HUB	CMOS	TX	SOIC	INDNS-O	28	48	495	0	
														48	545	0	
	HTOL2	125C/5.75V	PLD	MAX	CY7C342B-RMB	99279	9929 619919783	REPROG.PAL	CMOS	TX	WPGA	ALPHA-X	68	96	320	0	
	PCT	121C/100%RH	IPD	PCTRL	CY7C69100	98352	9852 519816422	MICROCTRL	FAMOS	TX	PDIP	INDNS-O	24	168	49	0	
														288	49	0	
				USB	CY7C63001A-SC	MR93015	9926 619918207	USB	CMOS	TX	SOIC	CSPI-R	20	168	44	0	
					CY7C65113-SC	MR92166	9916 619910306	USB HUB	CMOS	TX	SOIC	ALPHA-X	28	168	44	1	1 Bent Leads
					CY7C66013-PVC	99274	9928 619919239	FULL SP USB	CMOS	TX	SSOP	CSPI-R	48	168	48	0	
					CY7C66113-PVC	99241	9925 619916424	FULL SP USB	CMOS	TX	SSOP	CSPI-R	56	168	48	0	
	T/S	-55C TO 150C	IPD	USB	CY7C66113-PVC	99241	9925 619916424	FULL SP USB	CMOS	TX	SSOP	CSPI-R	56	100	50	0	
														200	50	0	
	TC2	-65C TO 150C	IPD	PCTRL	CY7C69100	98352	9852 519816422	MICROCTRL	FAMOS	TX	PDIP	INDNS-O	24	300	50	0	
				USB	CY7C63001A-SC	MR93016	9926 619918207	USB	CMOS	TX	SOIC	CSPI-R	20	300	45	0	
					CY7C63101A-SC	MR92069	9912 619906570	USB	CMOS	TX	SOIC	CSPI-R	24	300	45	0	
					CY7C65113-SC	MR92167	9916 619910306	USB HUB	CMOS	TX	SOIC	ALPHA-X	28	300	45	0	
					CY7C66013-PVC	99274	9928 619919239	FULL SP USB	CMOS	TX	SSOP	CSPI-R	48	300	48	0	

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FAMOS-P26	TC2	-65C TO 150C	IPD	USB	CY7C66113-PVC	99241	9925 619916424	FULL SP USB CMOS		TX	SSOP	CSPI-R	56	300	50	0	
							619916487	FULL SP USB CMOS		TX	SSOP	CSPI-R	56	300	50	0	
							619916488	FULL SP USB CMOS		TX	SSOP	CSPI-R	56	300	49	0	

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FLASH-FL28D	HAST	140C/5.5V	PLD	FLASH	CY7C371-JC	MR92186	9916 619910273	32-MCEL FL	CMOS	TX	PLCC	ALPHA-X	44	128	45	0	
	HTS2	150C/NO BIAS	PLD	FLASH	CY7C371-AC	MR93047	9926 619917919	32-MCEL FL	CMOS	TX	TQFP	KOREA-Q	44	500 1000	45 45	0 0	
			PLD		PALC22V10D-JC	MR93029	9924 619916273	FLASH ERAS.	CMOS	TX	PLCC	ALPHA-X	28	500 1000	45 45	0 0	
	PCT	121C/100%RH	PLD	FLASH	CY7C371-AC	MR93044	9926 619917919	32-MCEL FL	CMOS	TX	TQFP	KOREA-Q	44	168	45	0	
					CY7C375I-AC	MR93103	9927 619917921	128 MCEL FL	CMOS	TX	TQFP	KOREA-Q	160	168	45	0	
			PLD		PALC22V10D-7JC	MR93188	9930 519912784	FLASH ERAS.	CMOS	TX	PLCC	INDNS-O	28	168	45	0	
					PALC22V10D-JC	MR93027	9924 619916273	FLASH ERAS.	CMOS	TX	PLCC	ALPHA-X	28	168	45	0	
	TC2	-65C TO 150C	PLD	FLASH	CY7C371-AC	MR93045	9926 619917919	32-MCEL FL	CMOS	TX	TQFP	KOREA-Q	44	300	45	0	
					CY7C371-JC	MR92185	9916 619910273	32-MCEL FL	CMOS	TX	PLCC	ALPHA-X	44	300	45	0	
					CY7C375I-AC	MR93104	9927 619917921	128 MCEL FL	CMOS	TX	TQFP	KOREA-Q	160	300	45	0	
			PLD		PALC22V10D-7JC	MR93189	9930 519912784	FLASH ERAS.	CMOS	TX	PLCC	INDNS-O	28	300	45	0	
					PALC22V10D-JC	MR93028	9924 619916273	FLASH ERAS.	CMOS	TX	PLCC	ALPHA-X	28	300	45	0	

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SMT	TC	-40C TO 125C	MPD	MTI	CYM1464PD	99307	9928 349900226	512K x 8 SM NA	NA	NA	DIP	USA-AP	100 500	16 16	0 0		
					CYM1481LPS	99307	9928 349900221	2M x 8 SM NA	NA	NA	SIP	USA-AP	100 500	16 16	0 0		
					CYM1851PM	99307	9928 349900227	1M x 32 SM NA	NA	NA	SIM	USA-AP	100 500	16 16	0 0		

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Technology	Test	Test Condition	Divi- sion	Func- tion	Device	Eval#	D/C	Assembly Lot No	Description	Pro- cess	Wfr Loc	Pkg type	Assy Loc	No Pin	Dura tion	Qty Test	Qty Fail	Fail Mode
SRAM/LOGIC-L27	PCT	121C/100%RH	IPD	FCT	CY74FCT2646ATQC	MR92138	9917	619910754	8 BIT REG.	CMOS	MN	SSOP	CSPI-R	24	168	42	0	
	TC2	-65C TO 150C	IPD	FCT	CY74FCT162827TP	MR92051	9915	619908472	10 BIT REG.	CMOS	MN	SSOP	CSPI-R	56	300	45	0	

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SRAM/LOGIC-L28	HTOL	150C/3.8V	TTD	TTECH	CY2212PVC	99057	9915 619909702	CLOCK	CMOS	TX	SOIC	CSPI-R	48	48	118	0	
														48	298	0	1 EOS
														48	299	0	
														48	299	0	
	PCT	121C/100%RH	IPD	FCT	CY74FCT2245ATPV	MR91150	9906 619903166	8 BIT TRAN.	CMOS	TX	SSOP	MALAY-U	20	168	30	0	
			TTD	TTECH	CY2212PVC	99057	9915 619909702	CLOCK	CMOS	TX	SOIC	CSPI-R	48	168	48	0	
					CY2277APAC	MR93039	9928 619918960	CLOCK SYN.	CMOS	TX	TSSO	CSPI-R	48	168	45	0	
					CY2287PVC	MR93010	9927 619918212	CLOCK SYN.	CMOS	TX	SSOP	CSPI-R	56	168	45	0	
					CY2318PVC	MR93144	9930 619920598	CLOCK	CMOS	TX	TSOP	CSPI-R	48	168	45	0	
	TC2	-65C TO 150C	IPD	FCT	CY74FCT2245ATPV	MR91151	9906 619903166	8 BIT TRAN.	CMOS	TX	SSOP	MALAY-U	20	300	43	0	
					CY74FCT257ATQC	MR91148	9904 619901722		CMOS	TX	SSOP	MALAY-U	16	300	43	0	
			TTD	TTECH	CY2212PVC	99057	9915 619909702	CLOCK	CMOS	TX	SOIC	CSPI-R	48	300	48	0	
					CY2277APAC	99199	9918 619909832M	CLOCK SYN.	CMOS	TX	TSSO	CSPI-R	48	300	50	0	
														300	50	0	
						MR93040	9928 619918960	CLOCK SYN.	CMOS	TX	TSSO	CSPI-R	48	300	45	0	
					CY2287PVC	MR93011	9927 619918212	CLOCK SYN.	CMOS	TX	SSOP	CSPI-R	56	300	45	0	

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Technology	Test	Test Condition	Divi- sion	Func- tion	Device	Eval#	D/C	Assembly Lot No	Description	Pro- cess	Wfr Loc	Pkg type	Assy Loc	No Pin	Dura tion	Qty Test	Qty Fail	Fail Mode
SRAM/LOGIC-L31	PCT	121C/100%RH	IPD	FCT	CY74FCT16244ATP	MR92083	9804	349800047	16-BIT	CMOS	MN	SSOP	MALAY-U	48	168	45	0	
	TC2	-65C TO 150C	IPD	FCT	CY74FCT16244ATP	MR92084	9804	349800047	16-BIT	CMOS	MN	SSOP	MALAY-U	48	300	45	0	

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SRAM/LOGIC-R28	HAST	140C/5.5V	DCD	DPORT	CY7C006-JC	MR93201	9929	619920470	16K x 8 DP	CMOS	TX	PLCC	PHIL-M	68	128	45	0		
					CY7C024-JC	MR93195	9930	619919330	4K x 16 DP	CMOS	TX	PLCC	KOREA-A	84	0	44	0		
					CY7C136-JC	MR93239	9929	519912467	2K x 8 DP	CMOS	TX	PLCC	INDNS-O	52	128	45	0		
					CY7C136-JI	MR93067	9926	519910954	2K x 8 DP	CMOS	TX	PLCC	INDNS-O	52	128	45	0		
			MPD	COMDTY	CY7C188-VC	MR92038	9914	619907801	32K x 9	CMOS	TX	SOJ	CSPI-R	32	128	45	0		
					CY7C195-VC	MR92193	9837	519807582	64K x 4	CMOS	MN	SOJ	INDNS-O	28	128	45	1 1	Unknown Cause	
	HTOL	150C/5.75V	DCD	DPORT	CY7C136-JC	MR92204	9912	519903133	2K x 8 DP	CMOS	MN	PLCC	INDNS-O	52	48 96 500 1000	150 150 150 150	0 0 0 0		
					FIFO	CY7C433-LM	99195	9918	619911057	4Kx9 FIFO	CMOS	TX	LCC	ALPHA-X	32	48 48 48 48 80 500	140 212 212 212 228 120 120	0 0 0 0 0 0 0	
					CY7C433-LMB	99195	9918	619911057	4Kx9 FIFO	CMOS	TX	LCC	ALPHA-X	32	184 48 48 80 184 500	48 175 180 660 120 48 120	0 0 0 0 0 0 0		
					CY7C454-LMB	99175	9919	619911754	4Kx9 FIFO	CMOS	TX	LCC	ALPHA-X	32	48 48 48 80 184 500	175 180 660 120 48 120	0 0 0 0 0 0		
					CY7C457-JC	99301	9907	519902406	2Kx18 FIFO	CMOS	TX	PLCC	INDNS-O	52	48 48	299 584	0 6 0 6	EOS EOS	
			MPD	COMDTY	CY7C188-VC	99173	9914	619909331N	32K x 9	CMOS	TX	SOJ	CSPI-R	32	48	3156	0		
							9915	619909141N	32K x 9	CMOS	TX	SOJ	CSPI-R	32	48	3055	0		
							9923	619913693N	32K x 9	CMOS	TX	SOJ	CSPI-R	32	48	3125	0		
		150C/6.5V	DCD	FIFO	CY7C4201-JC	99172	9917	619910445Q	256x9 FIFO	CMOS	TX	PLCC	ALPHA-X	32	48	623	0		

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Technology	Test	Test Condition	Division	Function	Device	Eval#	D/C	Assembly Lot No	Description	Process	Wfr Loc	Pkg type	Assy Loc	No Pin	Dura tion	Qty Test	Qty Fail	Fail Mode
SRAM/LOGIC-R28	HTOL	150C/6.5V	DCD	FIFO	CY7C4241-JC	99172	9917	619910410Q	4Kx9 FIFO	CMOS	TX	PLCC	USA-C	32	48	608	0	
					CY7C4245-JC	99172	9907	619902975	4Kx18 FIFO	CMOS	TX	PLCC	PHIL-M	68	48	576	0	
								619902976	4Kx18 FIFO	CMOS	TX	PLCC	PHIL-M	68	48	538	0 1	EOS
Cause					CY7C4245V-ASC	99171	9917	619910524	4Kx18 FIFO	CMOS	MN	TQFP	KOREA-Q	64	48	430	1 1	EOS /1 Unknown
								619910524N	4Kx18 FIFO	CMOS	MN	TQFP	KOREA-Q	64	48	118	0	
								619910525	4Kx18 FIFO	CMOS	MN	TQFP	KOREA-Q	64	48	240	0	
								619910525N	4Kx18 FIFO	CMOS	MN	TQFP	KOREA-Q	64	48	108 48 228	0 0 1	EOS
								619910526	4Kx18 FIFO	CMOS	MN	TQFP	KOREA-Q	64	48	311	0	
								619910526N	4Kx18 FIFO	CMOS	MN	TQFP	KOREA-Q	64	48	287	0	
							9926	619917340	4Kx18 FIFO	CMOS	MN	TQFP	KOREA-Q	64	48	144	0	
								619917340N	4Kx18 FIFO	CMOS	MN	TQFP	KOREA-Q	64	48	421 48 432 48 481	0 0 0 0	
		150C/7.0V	DCD	DPORT	CY7C025-AC	99255	9925	619916107N	8K x 16 DP	CMOS	TX	TQFP	KOREA-Q	100	84	1055	0	
								619916108N	8K x 16 DP	CMOS	TX	TQFP	KOREA-Q	100	84	421 84 638	0 0 0	
								619916300N	8K x 16 DP	CMOS	TX	TQFP	KOREA-Q	100	84	382 84 650	0 0 0	
	HTS2	150C/NO BIAS	DCD	DPORT	CY7C136-JI	MR93068	9926	519910954	2K x 8 DP	CMOS	TX	PLCC	INDNS-O	52	500 1000	45 45	0 0	
	PCT	121C/100%RH	DCD	DPORT	CY7C006-JC	MR93199	9929	619920470	16K x 8 DP	CMOS	TX	PLCC	PHIL-M	68	168	45	0	
					CY7C024-JC	MR93193	9930	619919330	4K x 16 DP	CMOS	TX	PLCC	KOREA-A	84	168	45	0	
					CY7C0251-AC	MR93171	9925	619915661	8K x 16 DP	CMOS	TX	TQFP	TAIWAN-G	100	168	44	0	
					CY7C136-JI	MR93065	9926	519910954	2K x 8 DP	CMOS	TX	PLCC	INDNS-O	52	168	45	0	

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SRAM/LOGIC-R28	PCT	121C/100%RH	DCD	FIFO	CY7C4211-AC	MR93205	9931 619919397	512x9 FIFO	CMOS	TX	TQFP	KOREA-Q	32	168	43	0	
					CY7C433-AC	MR92207	9915 619908948	4Kx9 FIFO	CMOS	TX	TQFP	KOREA-Q	32	168	45	0	
			MPD	COMDTY	CY7C187-PC	MR93177	9929 619919172	SML/64K	CMOS	TX	PDIP	ALPHA-X	22	168	45	0	
	TC2	-65 TO 150C	DCD	FIFO	CY7C433-LM	99195	9918 619911057	4Kx9 FIFO	CMOS	TX	LCC	ALPHA-X	32	100 1000	50 48	0 0	
					CY7C433-LMB	99195	9918 619911057	4Kx9 FIFO	CMOS	TX	LCC	ALPHA-X	32	100	46	0	
					CY7C454-LMB	99175	9919 619911754	4Kx9 FIFO	CMOS	TX	LCC	ALPHA-X	32	100 1000	48 48	0 0	
		-65C TO 150C	DCD	DPORT	CY7C024-JC	MR93194	9930 619919330	4K x 16 DP	CMOS	TX	PLCC	KOREA-A	84	300	45	0	
					CY7C0251-AC	MR93172	9925 619915661	8K x 16 DP	CMOS	TX	TQFP	TAIWAN-G	100	300	45	0	
					CY7C136-JC	MR92201	9912 519903133	2K x 8 DP	CMOS	MN	PLCC	INDNS-O	52	300	45	0	
			MPD	COMDTY	CY7C136-JI	MR93066	9926 519910954	2K x 8 DP	CMOS	TX	PLCC	INDNS-O	52	300	45	0	
					FIFO CY7C433-AC	MR92208	9915 619908948	4Kx9 FIFO	CMOS	TX	TQFP	KOREA-Q	32	300	45	0	
					CY7C185-VI	MR92063	9909 619903571	SML/64K	CMOS	TX	SOJ	CSPI-R	28	300	44	0	
					CY7C187-PC	MR93178	9929 619919172	SML/64K	CMOS	TX	PDIP	ALPHA-X	22	300	45	0	
					CY7C195-VC	MR92192	9827 519807582	64K x 4	CMOS	MN	SOJ	INDNS-O	28	300	45	0	

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SRAM/LOGIC-R31	TC2	-65C TO 150C	MPD	SYNC	CY7C1399-VI	MR91217	9910 619904878	32K x 8	CMOS	MN	SOJ	CSPI-R	28	300	45	0	

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SRAM/LOGIC-R32	HAST	140C/5.5V	MPD	COMDTY	CY62256-SNC	MR92104	9915 519906723	32K x 8	CMOS	CA	NSOI	INDNS-O	28	128	45	0	
	HTOL	150C/5.75V	MPD	COMDTY	CY62256-SNC	MR84060	9837 519811387	32K x 8	CMOS	CA	NSOI	INDNS-O	28	48	150	0	
														96	149	0	
														500	149	0	
														1000	149	0	
						MR91101	9853 519900063	32K x 8	CMOS	CA	NSOI	INDNS-O	28	48	150	0	
														96	150	0	
														500	150	0	
														1000	150	0	
	HTOL2	125C/6.5V	MPD	COMDTY	CY62256-SNC	99309	9927 519911667	32K x 8	CMOS	CA	NSOI	INDNS-O	28	48	1530	0	
Cratering	PCT	121C/100%RH	MPD	COMDTY	CY62256-SNC	MR92102	9915 519906723	32K x 8	CMOS	CA	NSOI	INDNS-O	28	168	45	1	1 Overbond /
					CY62256-SNI	MR93150	9929 519912201	32K x 8	CMOS	MN	NSOI	INDNS-O	28	168	45	0	
	TC2	-65C TO 150C	MPD	COMDTY	CY62256-SNC	99309	9927 519911667	32K x 8	CMOS	CA	NSOI	INDNS-O	28	300	48	0	
					CY62256-SNI	MR93151	9929 519912201	32K x 8	CMOS	MN	NSOI	INDNS-O	28	300	45	0	

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SRAM/LOGIC-R32D	HAST	140C/5.5V	MPD	COMDTY	CY7C199-ZC	MR92005	9912 619906781	32K x 8(5V)	CMOS	MN	TSOP	CSPI-R	28	128	44	0	
	HTOL	150C/5.75	DCD	FIFO	CY7C466A-LM	99197	9917 619910469	64Kx9 FIFO	CMOS	MN	LCC	ALPHA-X	32	48	351	0	
		150C/5.75V	DCD	FIFO	CY7C466A-LM	99197	9917 619910469	64Kx9 FIFO	CMOS	MN	LCC	ALPHA-X	32	48	10	0	
														48	646	0	
														80	120	0	
														500	120	0	
					CY7C466A-LMB	99197	9917 619910469	64Kx9 FIFO	CMOS	MN	LCC	ALPHA-X	32	184	48	0	
			MPD	COMDTY	CY7C199-VC	MR91080	9903 619900012	32K x 8(5V)	CMOS	MN	SOJ	CSPI-R	28	48	150	0	
														96	150	0	
														500	130	1	Plastic Package
Defect														1000	128	0	
	PCT	121C/100%RH	DCD	FIFO	CY7C4285-ASC	MR93157	9930 619919829	64Kx18 FIFO	CMOS	MN	TQFP	KOREA-Q	64	168	45	0	
			MPD	COMDTY	CY7C199-ZC	MR92003	9912 619906781	32K x 8(5V)	CMOS	MN	TSOP	CSPI-R	28	168	44	0	
	TC2	-65 TO 150C	DCD	FIFO	CY7C466A-LM	99197	9917 619910469	64Kx9 FIFO	CMOS	MN	LCC	ALPHA-X	32	100	50	0	
														1000	50	0	
					CY7C466A-LMB	99197	9917 619910469	64Kx9 FIFO	CMOS	MN	LCC	ALPHA-X	32	100	47	0	
		-65C TO 150C	DCD	FIFO	CY7C4285-ASC	MR93158	9930 619919829	64Kx18 FIFO	CMOS	MN	TQFP	KOREA-Q	64	300	45	0	
			MPD	COMDTY	CY7C199-ZC	MR92004	9912 619906781	32K x 8(5V)	CMOS	MN	TSOP	CSPI-R	28	300	45	0	
					SYNC	CY7C1399-VC	MR91193	9911 619905946	32K x 8	CMOS	MN	SOJ	CSPI-R	28	300	41	0

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SRAM/LOGIC-R42	HAST	140C/3.63V	MPD	COMDTY	CY7C62127V-BAI	99156	9915	619907694	1 MEG SRAM	CMOS	MN	SBGA	TAIWAN-T	48	128	47	0	
	HTOL	150C/3.8V	MPD	COMDTY	CY7C62127V-BAI	99156	9917	619907693	1 MEG SRAM	CMOS	MN	SBGA	TAIWAN-G TAIWAN-T	48 48	500 800	120 120	0 0	
								619907695	1 MEG SRAM	CMOS	MN	SBGA	TAIWAN-T	48	500	119	0	
		150C/5.75V	MPD	COMDTY	CY7C62127V-BAI	99156	9917	619907695	1 MEG SRAM	CMOS	MN	SBGA	TAIWAN-T	48	800	118	1	1 Solderability
	HTOL2	125C/6.5V	MPD	COMDTY	CY62148-SC	99283	9917	619910358	512K x 8	CMOS	MN	SOIC	TAIWAN-G	32	48	723	0	
							9924	619915603	512K x 8	CMOS	MN	SOIC	TAIWAN-G	32	48	604	0	
								619915603L	512K x 8	CMOS	MN	SOIC	TAIWAN-G	32	48	1290	0	
							9927	619918072	512K x 8	CMOS	MN	SOIC	TAIWAN-G	32	48	398	0	
	HTS	165C/NO BIAS	MPD	COMDTY	CY7C62127V-BAI	99156	9917	619907695	1 MEG SRAM	CMOS	MN	SBGA	TAIWAN-T	48	336	48	0	
	PCT	121C/100%RH	MPD	COMDTY	CY7C62127V-BAI	99156	9917	619907693	1 MEG SRAM	CMOS	MN	SBGA	TAIWAN-T	48	168	48	0	
			TTD	TTECH	CY2212SC	M99307		4916159-20	RAMBUS	CMOS	MN	SOIC	KOREA-A	16	168	100	0	
	T/S	-55C TO 150C	MPD	COMDTY	CY7C62127V-BAI	99156	9917	619907695	1 MEG SRAM	CMOS	MN	SBGA	TAIWAN-T	48	100 200	48 48	0 0	
	TC	-40C TO 125C	MPD	COMDTY	CY7C62127V-BAI	99156	9915	619907694	1 MEG SRAM	CMOS	MN	SBGA	TAIWAN-T	48	500 1500	48 48	0 0	
							9917	619907693	1 MEG SRAM	CMOS	MN	SBGA	TAIWAN-T	48	500 1500	48 48	0 0	
								619907695	1 MEG SRAM	CMOS	MN	SBGA	TAIWAN-T	48	500 1500	48 48	0 1	1 Missing Solder
Ball																		

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SRAM/LOGIC-R42D	HAST	140C/3.63V	MPD	COMDTY	CY7C1021V33-ZSC	MR93138	9927	619916650	64K x16	CMOS	MN	TSOP	KOREA-H	44	128	3	0		
															128	45	0		
					CY7C1333-AC	MR92097	9901	619817590	64K x 32	CMOS	MN	TQFP	CSPI-R	100	128	44	0		
					CY7C1338-AC	MR93086	9928	619918771	128K x 32	CMOS	MN	TQFP	CSPI-R	100	128	45	0		
					CY7C1353-AC	MR93099	9927	619917277	256K x 18	CMOS	MN	TQFP	CSPI-R	100	128	45	0		
				SYNC	CY7C1334-AC	MR93092	9926	619917220	64K x 32	CMOS	MN	TQFP	CSPI-R	100	128	45	0		

	HTOL	150C/3.8V	DCD	DPORT	CY7C028V-AC	99243	9916	619909588	64K x 16 DP	CMOS	MN	TQFP	TAIWAN-G	100	48	349	0		
Intermetallics			MPD	COMDTY	CY7C1021V33-VC	MR84082	9845	619811706	64K x16	CMOS	MN	SOJ	CSPI-R	44	48	150	0		
																96	150	0	
																500	126	0	
																1000	126	1	1 Excess
					CY7C1049V33-VC	99332	9936	619923872	512K x 8	CMOS	MN	SOJ	CSPI-R	36	48	3334	0		
								619923872N	512K x 8	CMOS	MN	SOJ	CSPI-R	36	48	960	0		

	HTS2	150C/NO BIAS	MPD	COMDTY	CY7C1325-AC	MR93035	9923	619908541	256K x 18	CMOS	MN	TQFP	CSPI-R	100	500	45	0		
															1000	45	0		

	PCT	121C/100%RH	MPD	COMDTY	CY7C1021V33-ZSC	MR93136	9927	619916650	64K x16	CMOS	MN	TSOP	KOREA-H	44	168	45	0		
					CY7C1325-AC	MR93033	9923	619908541	256K x 18	CMOS	MN	TQFP	CSPI-R	100	168	44	0		
					CY7C1333-AC	MR92095	9901	619817590	64K x 32	CMOS	MN	TQFP	CSPI-R	100	168	45	0		
					CY7C1338-AC	MR93084	9928	619918771	128K x 32	CMOS	MN	TQFP	CSPI-R	100	168	45	0		
					CY7C1353-AC	MR93097	9927	619917277	256K x 18	CMOS	MN	TQFP	CSPI-R	100	168	45	0		
				SYNC	CY7C1334-AC	MR93090	9926	619917220	64K x 32	CMOS	MN	TQFP	CSPI-R	100	168	45	0		

	TC2	-65C TO 150C	MPD	COMDTY	CY7C1021V33-ZSI	MR91105	9842	619811676	64K x16	CMOS	MN	TSOP	KOREA-H	44	300	45	0		

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SRAM/LOGIC-R42D	TC2	-65C TO 150C	MPD	COMDTY	CY7C1021V33-ZSI	MR92017	9909	619904569	64K x16	CMOS	MN	TSOP	CSPI-R	44	300	45	0	
					CY7C1325-AC	MR93034	9923	619908541	256K x 18	CMOS	MN	TQFP	CSPI-R	100	300	45	0	
					CY7C1333-AC	MR92096	9901	619817590	64K x 32	CMOS	MN	TQFP	CSPI-R	100	300	45	0	
					CY7C1338-AC	MR93085	9928	619918771	128K x 32	CMOS	MN	TQFP	CSPI-R	100	300	45	0	
					CY7C1353-AC	MR93098	9927	619917277	256K x 18	CMOS	MN	TQFP	CSPI-R	100	300	45	0	
				SYNC	CY7C1334-AC	M99239	9909	619901398	64K x 32	CMOS	MN	TQFP	CSPI-R	100	300	200	0	
						MR93091	9926	619917220	64K x 32	CMOS	MN	TQFP	CSPI-R	100	300	45	0	

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SRAM/LOGIC-R42HD	HAST	140C/5.5V	MPD	COMDTY	CY7C1009-VC	MR93005	9926	619916573	256K x 4	CMOS	MN	SOJ	CSPI-R	32	128	45	0	
					CY7C1021-VI	MR93125	9930	619919776	64K x16	CMOS	MN	SOJ	CSPI-R	44	128	45	0	
					CY7C1049-VCB	MR92076	9914	619905722	512K x 8	CMOS	MN	SOJ	CSPI-R	36	128	45	0	
					MR93118	9930	619918414	512K x 8	CMOS	MN	SOJ	CSPI-R	36	128	45	0		
					CY7C199-VC	MR93073	9929	619920539	32K x 8(5V)	CMOS	MN	SOJ	CSPI-R	28	128	45	0	

	HTOL	150C/5.75V	DCD	DPORT	CY7C038-AC	99182	9920	619912281	64K x 18 DP	CMOS	MN	TQFP	TAIWAN-G	100	48	403	0	
														48	599	0		
			MPD	COMDTY	CY7C1009-VC	MR93007	9926	619916573	256K x 4	CMOS	MN	SOJ	CSPI-R	32	48	150	0	
														500	150	0		
					CY7C1021-VC	99194	9925	619913720	64K x16	CMOS	MN	SOJ	CSPI-R	44	48	1818	0	
					MR92047	9911	619816998	64K x16	CMOS	MN	SOJ	CSPI-R	44	48	150	0		
														96	150	0		
														500	150	0		
														1000	150	0		
					CY7C109-VC	99194	9928	519912164	128K x 8(5)	CMOS	MN	SOJ	INDNS-O	32	48	3290	0	
					MR91073	9904	519901259	128K x 8(5)	CMOS	MN	SOJ	INDNS-O	32	48	150	0		
														96	150	0		
														500	149	0		
														1000	149	0		
					MR92120	9912	519905501	128K x 8(5)	CMOS	MN	SOJ	INDNS-O	32	48	150	0		
														96	150	0		
														500	149	0		
														1000	1000	0		
		150C/6.5V	DCD	DPORT	CY7C009-AC	99246	9922	619913312	128K x 8 DP	CMOS	MN	TQFP	TAIWAN-G	100	48	353	0	
					CY7C028-AC	99246	9919	619911166	64K x 16 DP	CMOS	MN	TQFP	TAIWAN-G	100	48	360	0	
					CY7C038-AC	99246	9915	619908933	64K x 18 DP	CMOS	MN	TQFP	TAIWAN-G	100	48	354	0	

	HTS2	150C/NO BIAS	MPD	COMDTY	CY7C1009-VC	MR93006	9926	619916573	256K x 4	CMOS	MN	SOJ	CSPI-R	32	500	45	0	
														1000	44	0		

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SRAM/LOGIC-R42HD	HTS2	150C/NO BIAS	MPD	COMDTY	CY7C199-VC	MR93074	9929	619920539	32K x 8(5V)	CMOS	MN	SOJ	CSPI-R	28	500 1000	45 45	0 0	
	PCT	121C/100%RH	MPD	COMDTY	CY7C1009-VC	MR93003	9926	619916573	256K x 4	CMOS	MN	SOJ	CSPI-R	32	168	45	0	
					CY7C1021-VI	MR93123	9930	619919776	64K x16	CMOS	MN	SOJ	CSPI-R	44	168	45	0	
					CY7C1049-VCB	MR93116	9930	619918414	512K x 8	CMOS	MN	SOJ	CSPI-R	36	168	45	0	
					CY7C109-ZC	MR93217	9928	619918244	128K x 8(5)	CMOS	MN	SOJ	KOREA-GQ	32	168	44	0	
					CY7C199-VC	MR93071	9929	619920539	32K x 8(5V)	CMOS	MN	SOJ	CSPI-R	28	168	45	0	
	TC2	-65C TO 150C	MPD	COMDTY	CY7C1009-VC	MR93004	9926	619916573	256K x 4	CMOS	MN	SOJ	CSPI-R	32	300	45	0	
					CY7C1021-VC	MR92044	9911	619816998	64K x16	CMOS	MN	SOJ	CSPI-R	44	300	44	0	
					CY7C1021-ZSC	99275	9905	619902605	64K x16	CMOS	MN	TSOP	KOREA-H	44	300	50	0	
								619902799	64K x16	CMOS	MN	TSOP	KOREA-H	44	300	49	0	
								9906 619903217	64K x16	CMOS	MN	TSOP	KOREA-H	44	300	50	0	
					CY7C109-VC	MR91071	9904	519901259	128K x 8(5)	CMOS	MN	SOJ	INDNS-O	32	300	50	0	
						MR92117	9912	519905501	128K x 8(5)	CMOS	MN	SOJ	INDNS-O	32	300	45	0	
					CY7C109-ZC	MR92011	9908	619903670	128K x 8(5)	CMOS	MN	SOJ	PHIL-GW	32	300	45	0	
					CY7C199-VC	MR91244	9908	619901753	32K x 8(5V)	CMOS	MN	SOJ	ALPHA-X	28	300	45	0	

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Technology	Test	Test Condition	Division	Function	Device	Eval#	D/C	Assembly Lot No	Description	Process	Wfr Loc	Pkg type	Assy Loc	No Pin	Duration	Qty Test	Qty Fail	Fail Mode

SRAM/LOGIC-R52D	HAST	130/3.63V	DCD	DPORT	CY7C057V-AC	99202	9930	619920052	16/32K x 36	CMOS	MN	TQFP	TAIWAN-G	144	128	48	0	
		130C/3.63V	DCD	DPORT	CY7C057V-AC	99202	9920	619912249	16/32K x 36	CMOS	MN	TQFP	TAIWAN-G	144	128	47	0	
			MPD	COMDTY	CY7C1329-AC	99311	9906	619902690	64K x 32	CMOS	MN	TQFP	CSPI-R	100	128 256	48 48	0 0	
							9910	619903817	64K x 32	CMOS	MN	TQFP	CSPI-R	100	128	48	0	

2L1	HTOL	150C/3.8V	DCD	DPORT	CY7C057V-AC	99202	9920	619912249	16/32K x 36	CMOS	MN	TQFP	TAIWAN-G	144	80 500	389 385	0 1	Particle Defect
								619920052	16/32K x 36	CMOS	MN	TQFP	TAIWAN-G	144	48 80	784 390	0 1	Fa Pending, 99202-
														500	369	1	Gate Oxide Rupture (CDM)	
Cause																		
Cause			MPD	COMDTY	CY7C1329-AC	99311	9916	619909761	64K x 32	CMOS	MN	TQFP	CSPI-R	100	80 500	1196 799	0 0	
								619911324	64K x 32	CMOS	MN	TQFP	CSPI-R	100	80 500	1491 1199	1 3	Unkown Cause EOS/1 Unknown
								619911327	64K x 32	CMOS	MN	TQFP	CSPI-R	100	80 500	1640 1451	0 1	EOS/ 1 Unkown
Cause																		
FA99311-		150C/4.0V	DCD	DPORT	CY7C057V-AC	99202	9920	619912249	16/32K x 36	CMOS	MN	TQFP	TAIWAN-G	144	48	773	0	
		150C/4.5V	MPD	COMDTY	CY7C1329-AC	99311			64K x 32	CMOS	MN	TQFP	CSPI-R	100	48 48	997 1991	0 0	
							9916	619909761	64K x 32	CMOS	MN	TQFP	CSPI-R	100	48	1205	0	
							9917	619909776	64K x 32	CMOS	MN	TQFP	CSPI-R	100	48	871	0	
							9918	619911324	64K x 32	CMOS	MN	TQFP	CSPI-R	100	48	1584	1	Particle Defect
								619911327	64K x 32	CMOS	MN	TQFP	CSPI-R	100	48	1669	1	Fa Pending, 4BE1

	HTS	165C/NO BIAS	MPD	COMDTY	CY7C1329-AC	99311	9849	619815465	64K x 32	CMOS	MN	TQFP	CSPI-R	100	336	48	0	
							9851	619815797	64K x 32	CMOS	MN	TQFP	CSPI-R	100	336	48	0	

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Technology	Test	Test Condition	Divi- sion	Func- tion	Device	Eval#	Assembly D/C Lot No	Description	Pro- cess	Wfr Loc	Pkg type	Assy Loc	No Pin	Dura tion	Qty Test	Qty Fail	Fail Mode
SRAM/LOGIC-R52D	HTSSL	150C/3.63V	MPD	COMDTY	CY7C1329-AC	99311	9849 619815465	64K x 32	CMOS	MN	TQFP	CSPI-R	100	80 168	80 80	0 0	
							9851 619815797	64K x 32	CMOS	MN	TQFP	CSPI-R	100	80 168	80 80	0 0	
	PCT	121C/100%RH	DCD	DPORT	CY7C057V-AC	99202	9920 619912249	16/32K x 36	CMOS	MN	TQFP	TAIWAN-G	144	168	48	0	
							9930 619920052	16/32K x 36	CMOS	MN	TQFP	TAIWAN-G	144	168	50	0	
			MPD	COMDTY	CY7C1329-AC	99311	9906 619902690	64K x 32	CMOS	MN	TQFP	CSPI-R	100	168	48	0	
							9910 619903817	64K x 32	CMOS	MN	TQFP	CSPI-R	100	168	46	0 2	EOS
	TC2	-65C TO 150C	DCD	DPORT	CY7C057V-AC	99202	9920 619912249	16/32K x 36	CMOS	MN	TQFP	TAIWAN-G	144	300	48	1 1	Unknown Cause
			MPD	COMDTY	CY7C1329-AC	99311	9849 619815465	64K x 32	CMOS	MN	TQFP	CSPI-R	100	300	48	0	
							9851 619815797	64K x 32	CMOS	MN	TQFP	CSPI-R	100	300	45	0	

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Technology	Test	Test Condition	Divi- sion	Func- tion	Device	Eval#	Assembly D/C Lot No	Description	Pro- cess	Wfr Loc	Pkg type	Assy Loc	No Pin	Dura tion	Qty Test	Qty Fail	Fail Mode
SRAM/LOGIC-R52H	HTOL	150C/3.8V	MPD	COMDTY	CY62128V-ZIB	99321	619912362/	128K x 8	CMOS	MN	TSOP	CSPI-R	32	48 80	1414 1411	1 0	Particle Defect
							9924 619915039/	128K x 8	CMOS	MN	TSOP	CSPI-R	32	48 80	1433 1427	0 0	
							9926 619915042L	128K x 8	CMOS	MN	TSOP	CSPI-R	32	48 80	467 466	0 0	
	PCT	121C/100%RH	MPD	COMDTY	CY62128V-ZAIB	99302	9932 619921794	128K x 8	CMOS	MN	STSO	CSPI-R	32	168	50	0	
	TC2	-65C TO 150C	MPD	COMDTY	CY62128V-ZAIB	99302	9916 619906905	128K x 8	CMOS	MN	STSO	CSPI-R	32	300	15	0	
							619906918	128K x 8	CMOS	MN	STSO	CSPI-R	32	300	15	0	
							619907024	128K x 8	CMOS	MN	STSO	CSPI-R	32	300	15	0	
							619907025	128K x 8	CMOS	MN	STSO	CSPI-R	32	300	15	0	
							619907216	128K x 8	CMOS	MN	STSO	CSPI-R	32	300	15	0	
							619907217	128K x 8	CMOS	MN	STSO	CSPI-R	32	300	15	0	
							9917 619907218	128K x 8	CMOS	MN	STSO	CSPI-R	32	300	15	0	
							619909463	128K x 8	CMOS	MN	STSO	CSPI-R	32	300	15	0	
							9926 619916931	128K x 8	CMOS	MN	STSO	CSPI-R	32	300	15	0	
							619917084	128K x 8	CMOS	MN	STSO	CSPI-R	32	300	15	0	

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Technology	Test	Test Condition	Divi- sion	Func- tion	Device	Eval#	D/C	Assembly Lot No	Description	Pro- cess	Wfr Loc	Pkg type	Assy Loc	No Pin	Dura tion	Qty Test	Qty Fail	Fail Mode
SRAM/LOGIC-R52LD HTOL		150C/3.8V	MPD	COMDTY	CY62137VL-ZSIB	99261	9923	619913469	128K x 16	CMOS	MN	TSOP	CSPI-R	44	48	1783	0	
								619913470	128K x 16	CMOS	MN	TSOP	CSPI-R	44	48	2456	0	
							9924	619913465	128K x 16	CMOS	MN	TSOP	CSPI-R	44	48	2195	0	
								619913467	128K x 16	CMOS	MN	TSOP	CSPI-R	44	48	2073	1 1	Fab Defect
								619913696	128K x 16	CMOS	MN	TSOP	CSPI-R	44	48	709	1 1	Unknown Cause